Notice of References Cited

Application/Control No.

10/740 695

Examiner

Saif A. Alhija

Applicant(s)/Patent Under
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U:S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Tyrrell et al. "CSP Methods for Identifying Atomic Actions in the Design of Fault Tolerant Concurrent Systems" IEEE 1995				
	v					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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